

### Summary (ABSTRACT)

The present invention relates to a device for measuring the distribution of selected properties of materials, said device comprises an emitter of electromagnetic radiation and furthermore at least one sensor of a first type. The emitter emits electromagnetic radiation in a selected frequency range towards said materials and a sensor of the first type detects electromagnetic radiation in a selected frequency range coming from said materials. The detected electromagnetic radiation having been emitted by said emitter. The device also comprises means to generate a three dimensional image contour information regarding the said material's position in space, and an analyser which (a) receives information from said sensors and (b) processes this information and (c) generates signals containing information about the distribution of said properties as output. The invention also relates to a system and a method for measuring the distribution of selected properties of materials.